



YUYUE

16N65F

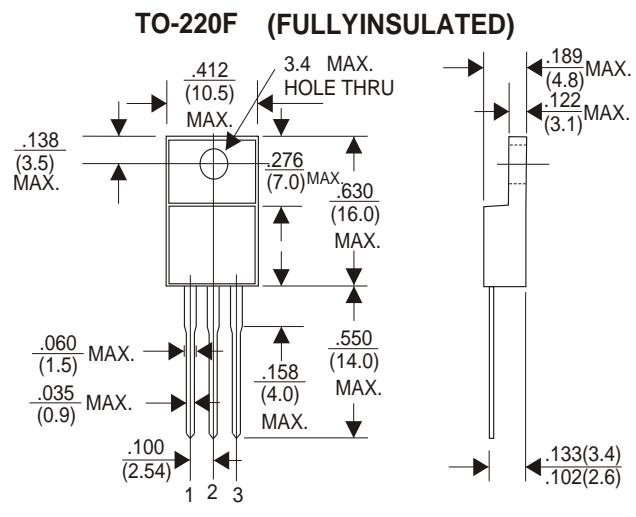
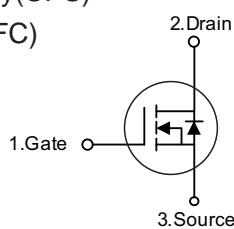
N-Channel Enhancement Mode MOSFET

Features

- 650V,16A
- $R_{DS(ON)} = 0.48$ (Typ.) @ $V_{GS} = 10V$, $I_D = 8A$
- Fast Switching
- Improved dv/dt Capability
- 100% Avalanche Tested

Application

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- Power Factor Correction (PFC)



Dimensions in inches and (millimeters)

Absolute Maximum Ratings ($T_C=25$ unless otherwise specified)

Symbol	Parameter		Max.	Units
V_{DSS}	Drain-Source Voltage		650	V
V_{GSS}	Gate-Source Voltage		± 30	V
I_D	Continuous Drain Current	$T_C = 25$	16	A
		$T_C = 100$	10	A
I_{DM}	Pulsed Drain Current ^{note1}		64	A
E_{AS}	Single Pulsed Avalanche Energy ^{note2}		461	mJ
P_D	Power Dissipation	$T_C = 25$	98	W
R_{JC}	Thermal Resistance, Junction to Case		1.3	/W
R_{JA}	Thermal Resistance, Junction to Ambient		62.5	/W
T_J, T_{STG}	Operating and Storage Temperature Range		-55 to +150	

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Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_D=250\mu\text{A}$	650	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=650\text{V}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	-	-	1	μA
I_{GSS}	Gate to Body Leakage Current	$V_{DS}=0\text{V}, V_{GS}= \pm 30\text{V}$	-	-	± 100	nA
On Characteristics						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static Drain-Source on-Resistance note3	$V_{GS}=10\text{V}, I_D=8\text{A}$	-	0.48	0.55	
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{DS}=25\text{V}, V_{GS}=0\text{V}, f=1.0\text{MHz}$	-	2740	-	pF
C_{oss}	Output Capacitance		-	214	-	pF
C_{rss}	Reverse Transfer Capacitance		-	15	-	pF
Q_g	Total Gate Charge	$V_{DD}=520\text{V}, I_D=16\text{A}, V_{GS}=10\text{V}$	-	71	-	nC
Q_{gs}	Gate-Source Charge		-	10	-	nC
Q_{gd}	Gate-Drain("Miller") Charge		-	32	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=325\text{V}, I_D=16\text{A}, R_G=25\Omega$	-	35	-	ns
t_r	Turn-on Rise Time		-	50	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	160	-	ns
t_f	Turn-off Fall Time		-	65	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_s	Maximum Continuous Drain to Source Diode Forward Current	-	-	16	-	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current	-	-	64	-	A
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS}=0\text{V}, I_{SD}=16\text{A}$	-	-	1.4	V
t_{rr}	Reverse Recovery Time	$V_{GS}=0\text{V}, I_S=16\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	430	-	ns
Q_{rr}	Reverse Recovery Charge		-	6.5	-	μC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2. EAS condition: $T_J = 25^\circ\text{C}$, $V_{DD} = 80\text{V}$, $V_G = 10\text{V}$, $L = 10\text{mH}$, $I_{AS} = 9.6\text{A}$

3. Pulse Test: Pulse Width 300 μs , Duty Cycle 1%

RATING AND CHARACTERISTIC CURVES (16N65F)

Figure 1: Output Characteristics

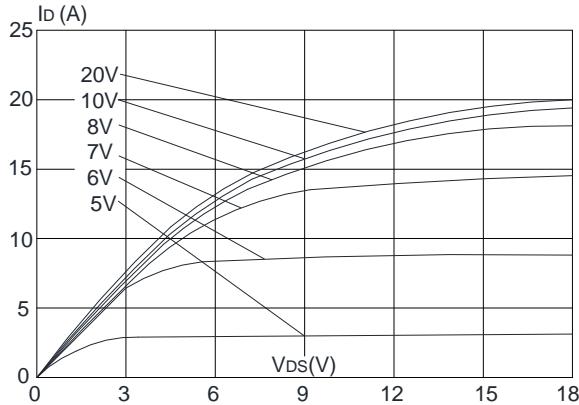


Figure 2: Typical Transfer Characteristics

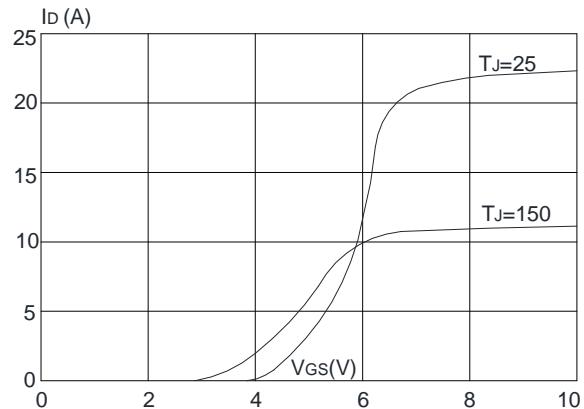


Figure 3: On-resistance vs. Drain Current

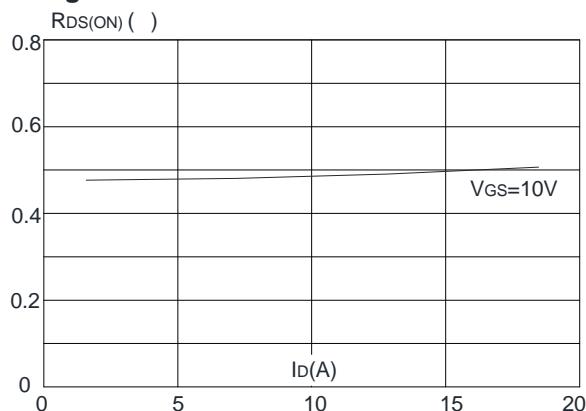


Figure 4: Body Diode Characteristics

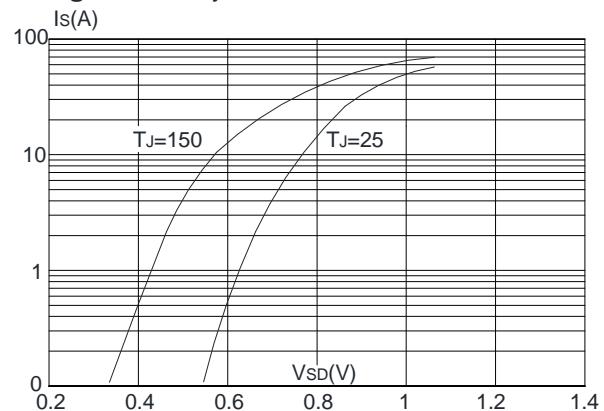


Figure 5: Gate Charge Characteristics

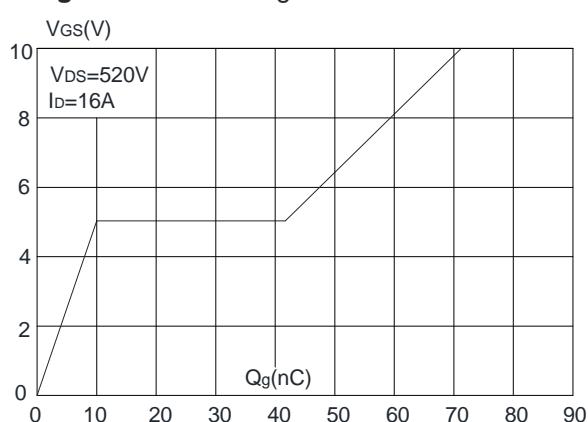
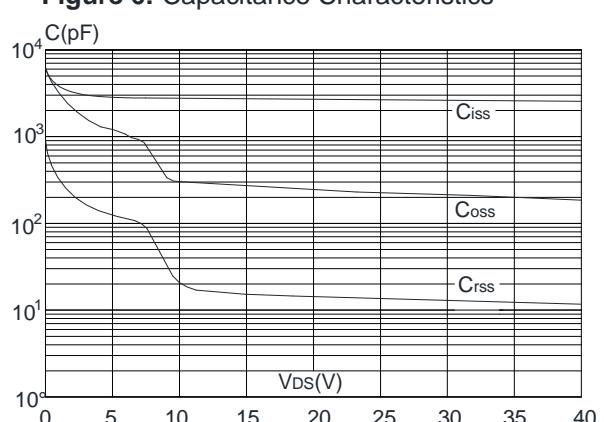


Figure 6: Capacitance Characteristics



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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

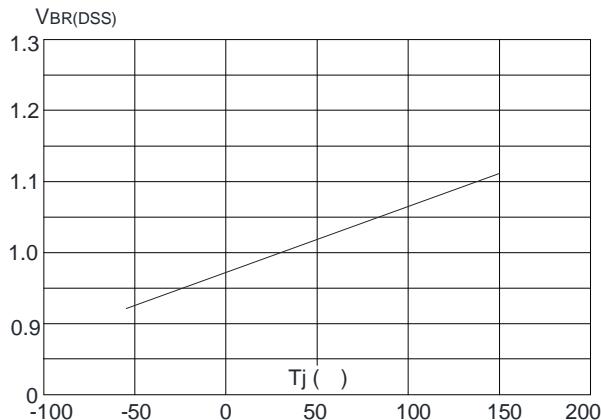


Figure 8: Normalized on Resistance vs. Junction Temperature

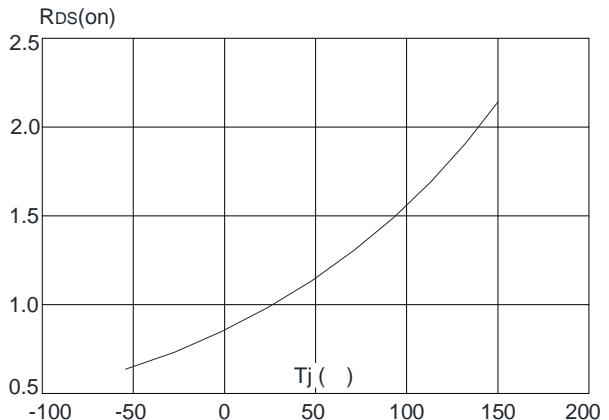


Figure 9: Maximum Safe Operating Area

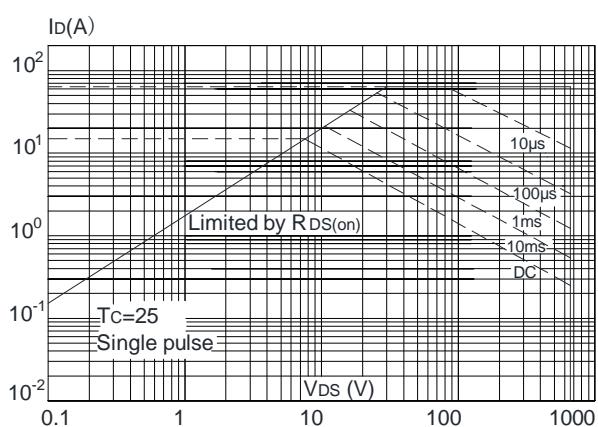


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

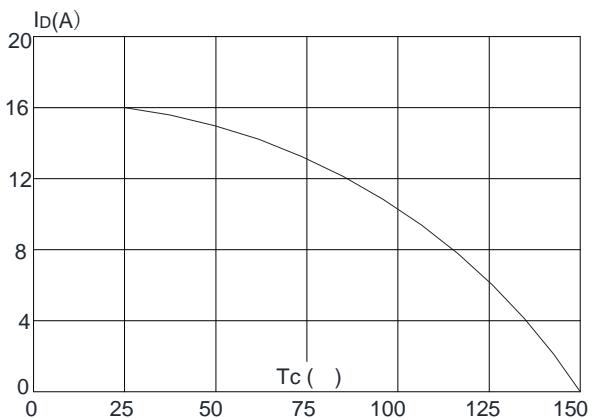


Figure 11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

